

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination VOORAKARANAM ET AL.	
		Examiner Hal D Wachsman	Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,625,785	09-2003	Chatterjee et al.	716/4
B	US-5,341,315	08-1994	Niwa et al.	714/738
C	US-4,991,176	02-1991	Dahbura et al.	714/738
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J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
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P					
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	Balivada et al., "Analog Testing with Time Response Parameters", 1996, IEEE Design & Test of Computers, pages 18-25.	
V	Voorakaranam et al., "Low-Cost Signature Testing of RF Circuits", no date on reference, pages 2-11.	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.